Contents

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	600	V
V_{GS}	Gate-source voltage	± 25	V
I_D	Drain current (continuous) at T_C = 25 °C	31.5	A
I_D	Drain current (continuous) at T_C = 100 °C	20	A
I_{DM} (1)	Drain current (pulsed)	126	A
P_{TOT}	Total dissipation at T_C = 25 °C	250	W
I_{AR}	Max current during repetitive or single pulse avalanche (pulse width limited by T_{jmax})	7	A
E_{AS}	Single pulse avalanche energy (starting T_J = 25 °C, I_D=I_{AS}, V_{DD}= 50 V)	345	mJ
dv/dt (2)	Peak diode recovery voltage slope	15	V/ns
dv/dt(3)	MOSFET dv/dt ruggedness	50	V/ns
T_{stg}	Storage temperature	-55 to 150	°C
T_j	Max. operating junction temperature	150	°C

1. Pulse width limited by safe operating area.
2. $I_{SD} \leq 31.5$ A, di/dt $\leq$ 400 A/µs, V_{DS} peak $\leq V_{(BR)DSS}$, V_{DD} = 80% $V_{(BR)DSS}$
3. $V_{DS} \leq 480$ V

Table 3. Thermal data

Symbol	Parameter	Value		Unit
		D^2PAK	TO-220	
$R_{thj\text{-}case}$	Thermal resistance junction-case max	0.5		°C/W
$R_{thj\text{-}amb}$	Thermal resistance junction-amb max		62.5	
$R_{thj\text{-}pcb}$ (1)	Thermal resistance junction-pcb max	**30**		

1. When mounted on 1 inch² FR-4, 2 Oz copper board.

2 Electrical characteristics

(T_{CASE} = 25 °C unless otherwise specified).

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage (V_{GS}= 0)	I_D = 1 mA	600			V
I_{DSS}	Zero gate voltage drain current (V_{GS} = 0)	V_{DS} = 600 V V_{DS} = 600 V, Tc=125 °C			1 100	µA µA
I_{GSS}	Gate body leakage current (V_{DS} = 0)	V_{GS} = ± 25 V			±100	nA
$V_{GS(th)}$	Gate threshold voltage	V_{DS} = V_{GS}, I_D = 250 µA	2	3	4	V
$R_{DS(on)}$	Static drain-source on-resistance	V_{GS} = 10 V, I_D= 14.5 A		0.092	0.105	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	V_{DS} =100 V, f=1 MHz, V_{GS}=0	-	2722	-	pF
C_{oss}	Output capacitance		-	173	-	pF
C_{rss}	Reverse transfer capacitance		-	1.75	-	pF
$C_{oss\ eq.}$ (1)	Equivalent capacitance time related	V_{GS} = 0, V_{DS} = 0 to 480 V	-	458	-	pF
$t_{d(on)}$	Turn-on delay time	V_{DD} = 300 V, I_D = 15.75 A, R_G=4.7 Ω, V_{GS}=10 V *(see Figure 19 and 14)*	-	18	-	ns
t_r	Rise time		-	36	-	ns
$t_{d(off)}$	Turn-off delay time		-	104	-	ns
t_f	Fall time		-	73	-	ns
Q_g	Total gate charge	V_{DD} = 480 V, I_D = 31.5 A V_{GS} =10 V *(see Figure 15)*	-	84	-	nC
Q_{gs}	Gate-source charge		-	14	-	nC
Q_{gd}	Gate-drain charge		-	45	-	nC
R_G	Intrinsic gate resistance	f = 1 MHz, gate DC Bias=0 test signal level=20 mV open drain	-	2.9	-	Ω

1. $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 6. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		31.5	A
I_{SDM}(1)	Source-drain current (pulsed)		-		126	A
V_{SD}(2)	Forward on voltage	I_{SD}= 31.5 A, V_{GS}=0	-		1.6	V
t_{rr}	Reverse recovery time	I_{SD}= 31.5 A, V_{DD}= 60 V di/dt = 100 A/µs, *(see Figure 16)*	-	412		ns
Q_{rr}	Reverse recovery charge		-	8		µC
I_{RRM}	Reverse recovery current		-	39		A
t_{rr}	Reverse recovery time	I_{SD}= 31.5 A,V_{DD}= 60 V di/dt=100 A/µs, T_j=150 °C *(see Figure 16)*	-	490		ns
Q_{rr}	Reverse recovery charge		-	10		µC
I_{RRM}	Reverse recovery current		-	43		A

1. Pulse width limited by safe operating area
2. Pulsed: Pulse duration = 300 µs, duty cycle 1.5%.

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

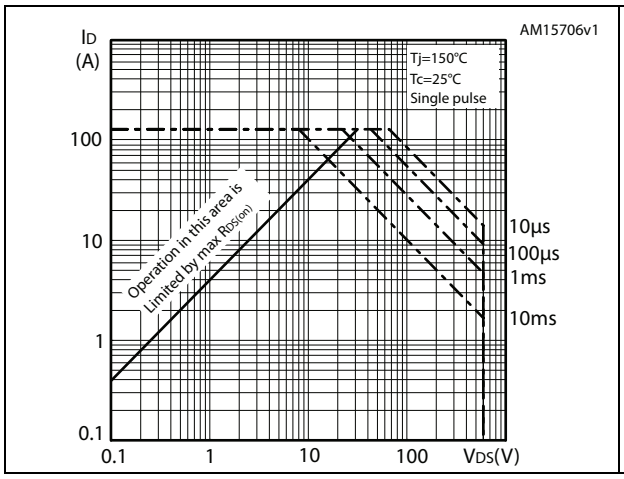


Figure 3. Thermal impedance

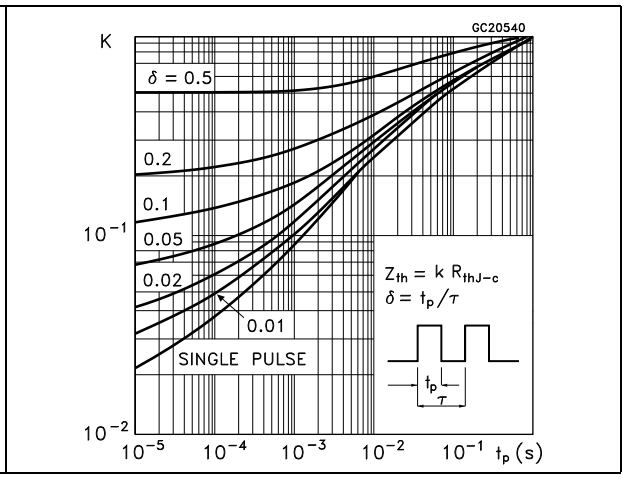


Figure 4. Output characteristics

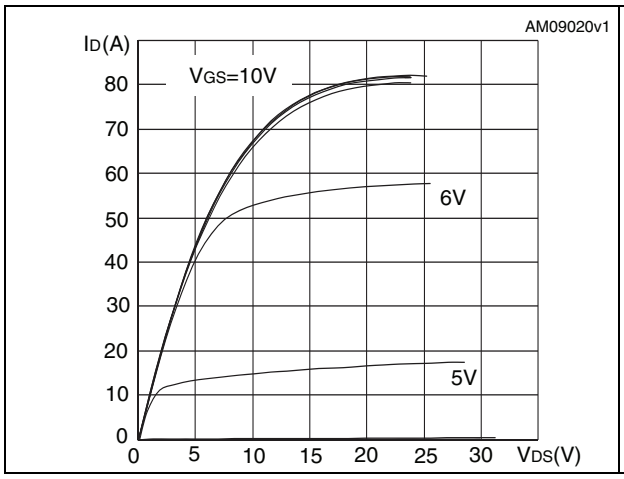


Figure 5. Transfer characteristics

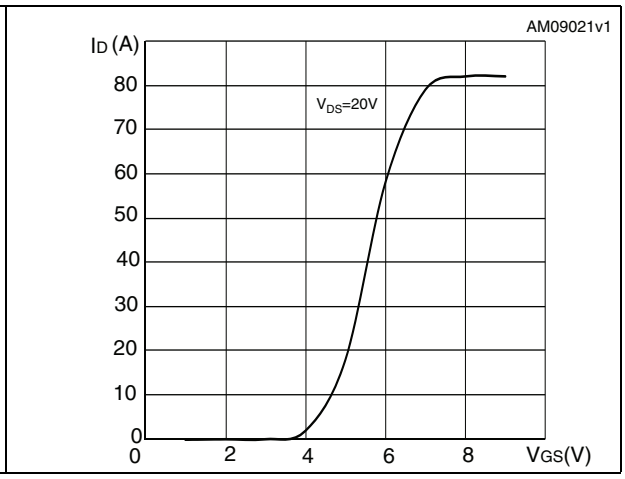


Figure 6. Gate charge vs gate-source voltage

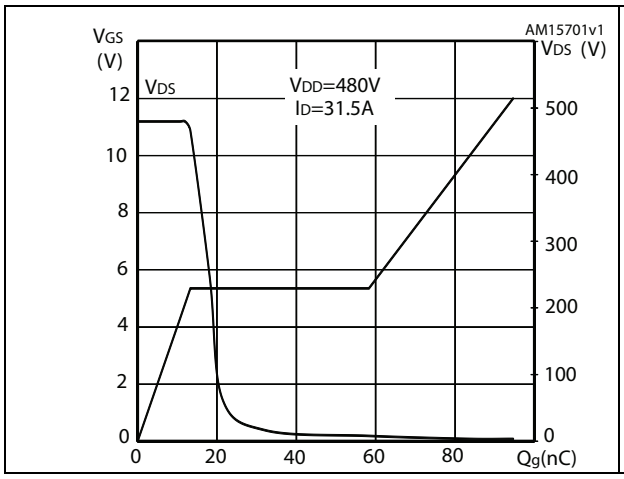


Figure 7. Static drain-source on-resistance

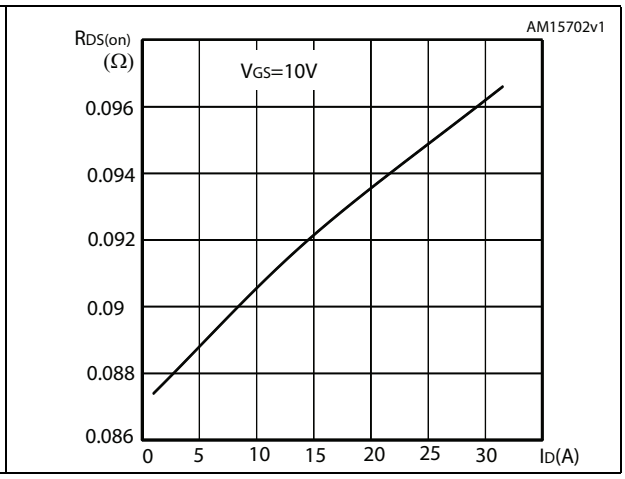


Figure 8. Capacitance variations

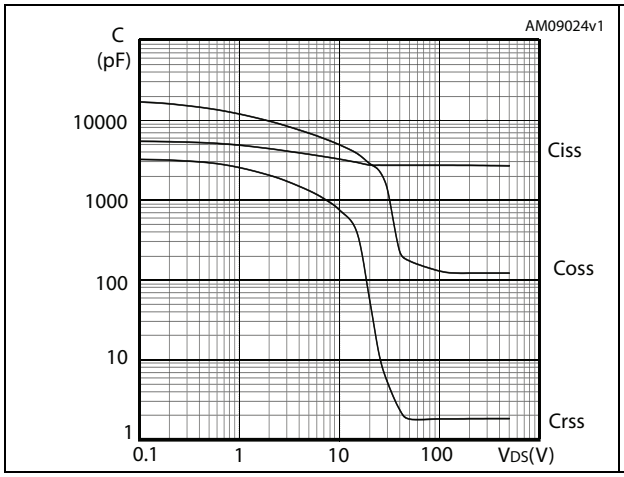


Figure 9. Output capacitance stored energy

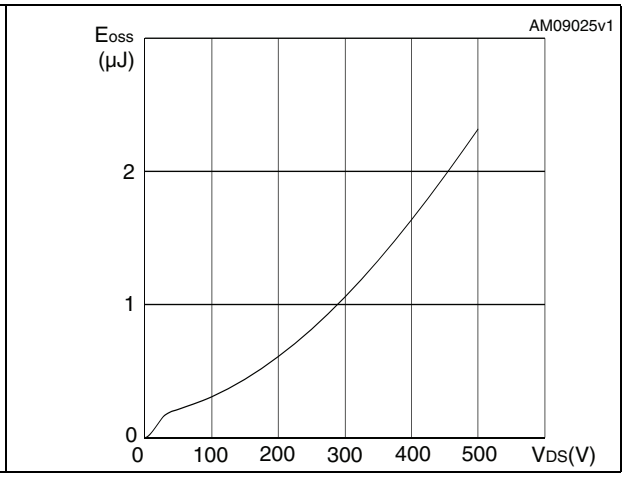


Figure 10. Normalized gate threshold voltage vs temperature

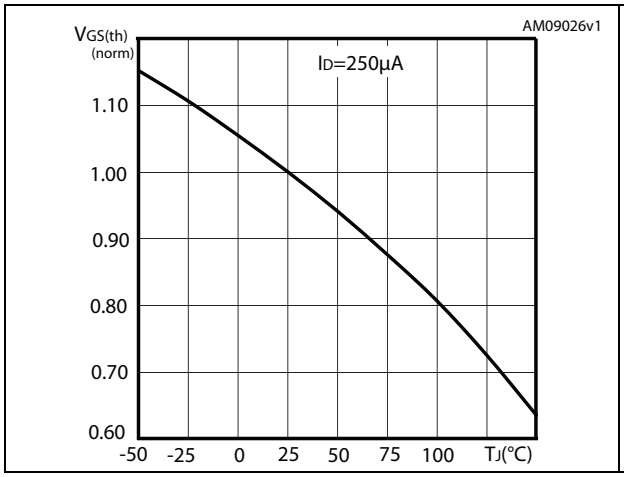


Figure 11. Normalized on-resistance vs temperature

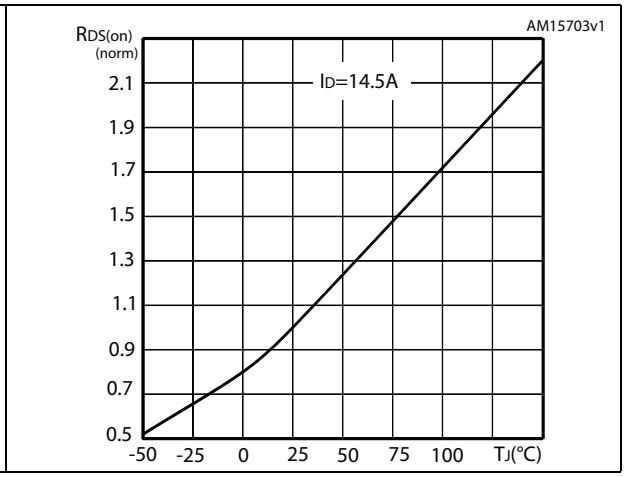


Figure 12. Normalized B_{VDSS} vs temperature

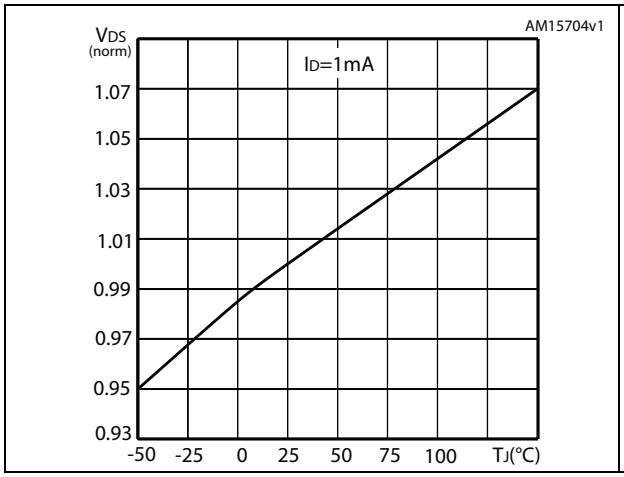
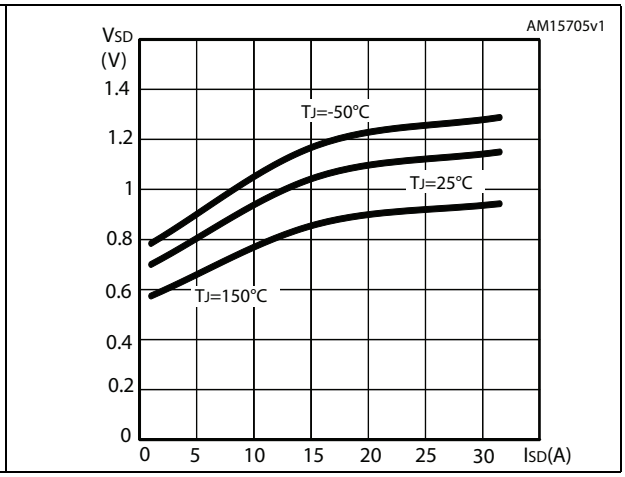


Figure 13. Source-drain diode forward characteristics



3 Test circuits

Figure 14. Switching times test circuit for resistive load

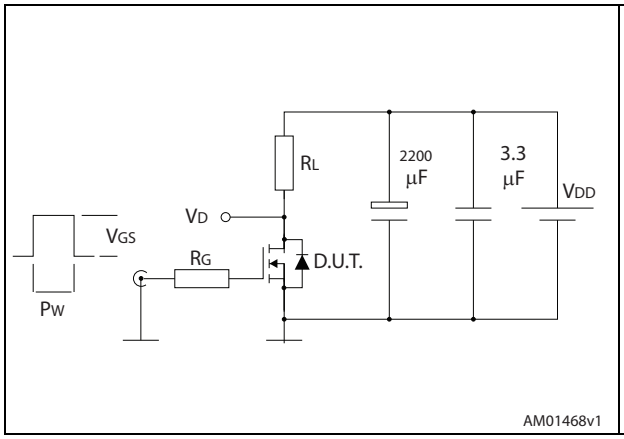


Figure 15. Gate charge test circuit

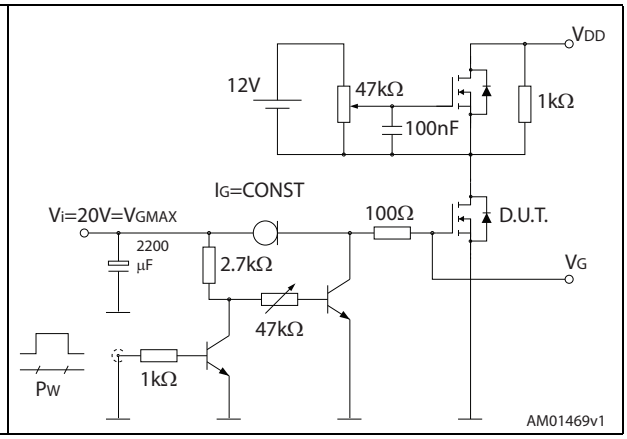


Figure 16. Test circuit for inductive load switching and diode recovery times

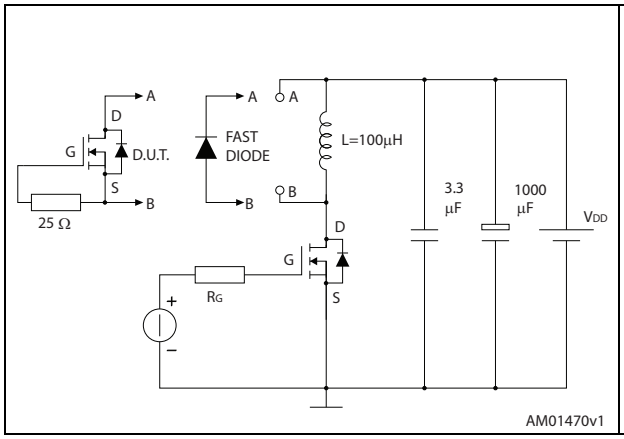


Figure 17. Unclamped inductive load test circuit

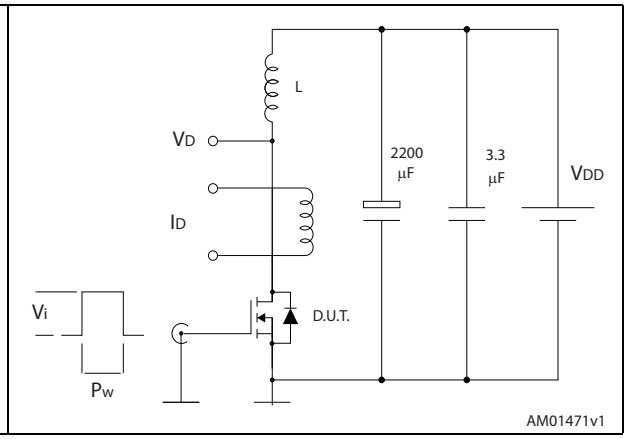


Figure 18. Unclamped inductive waveform

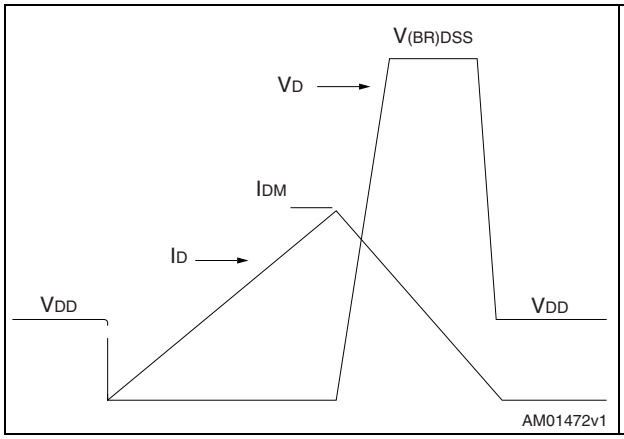
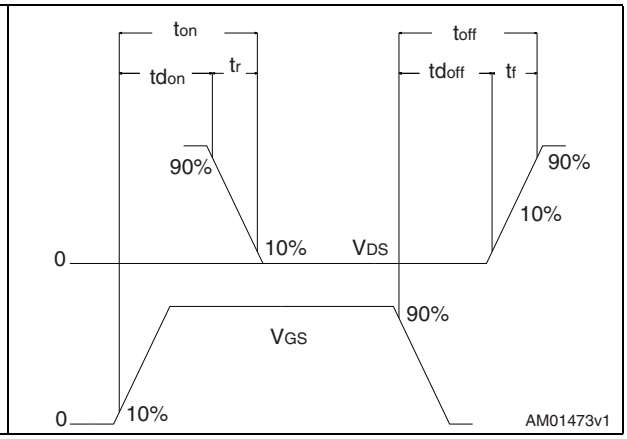


Figure 19. Switching time waveform



4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK® is an ST trademark.

4.1 D²PAK package information

Figure 20. D²PAK (TO-263) outline

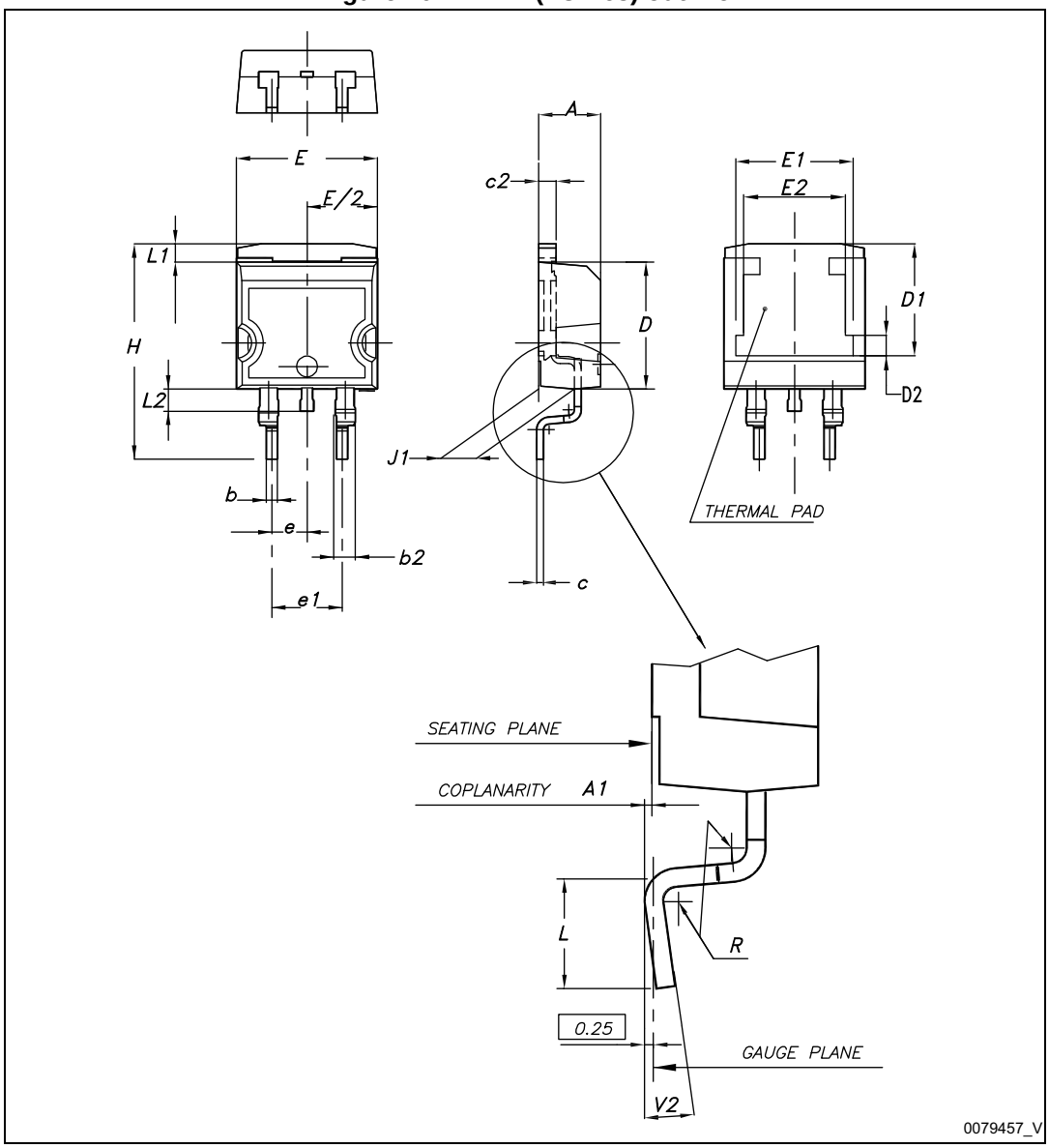
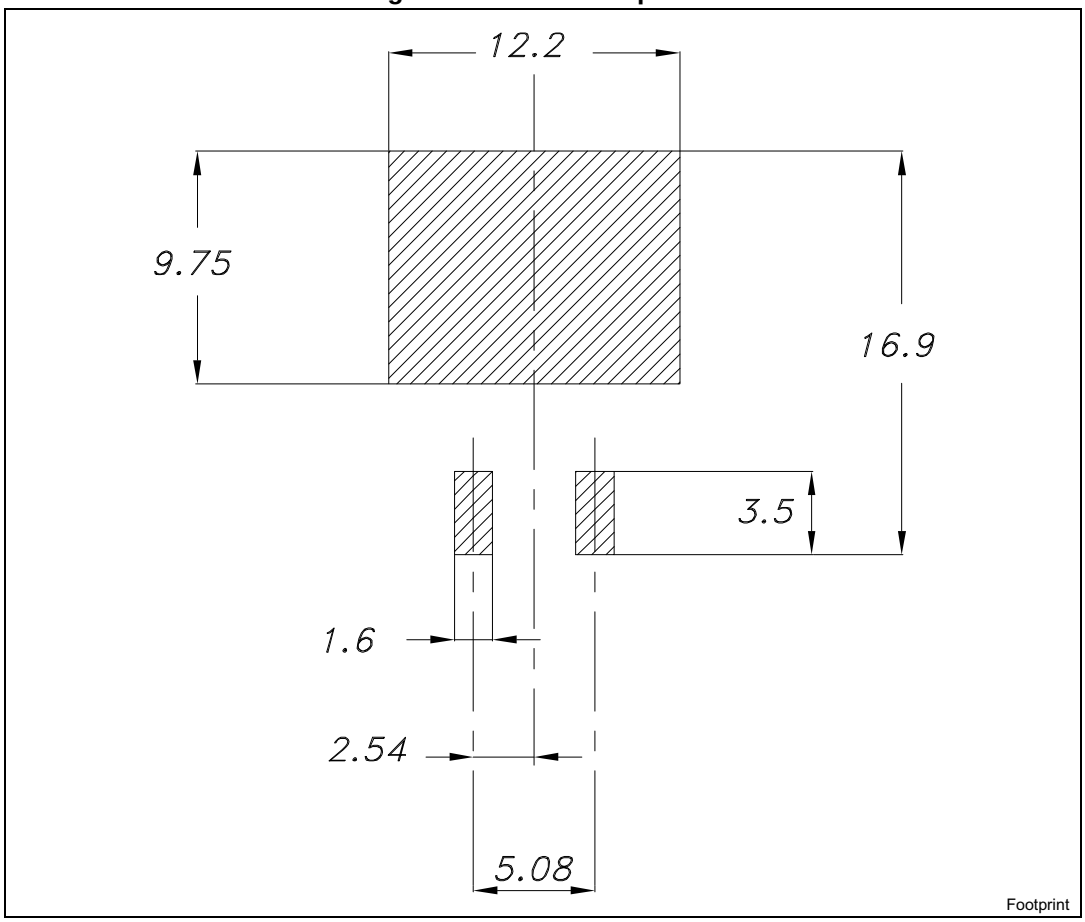


Table 7. D²PAK (TO-263) mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
A1	0.03		0.23
b	0.70		0.93
b2	1.14		1.70
c	0.45		0.60
c2	1.23		1.36
D	8.95		9.35
D1	7.50	7.75	8.00
D2	1.10	1.30	1.50
E	10		10.40
E1	8.50	8.70	8.90
E2	6.85	7.05	7.25
e		2.54	
e1	4.88		5.28
H	15		15.85
J1	2.49		2.69
L	2.29		2.79
L1	1.27		1.40
L2	1.30		1.75
R		0.4	
V2	0°		8°

Figure 21. D²PAK footprint[(a)]



a. All dimension are in millimeters

4.2 TO-220 package information

Figure 22. TO-220 type A outline

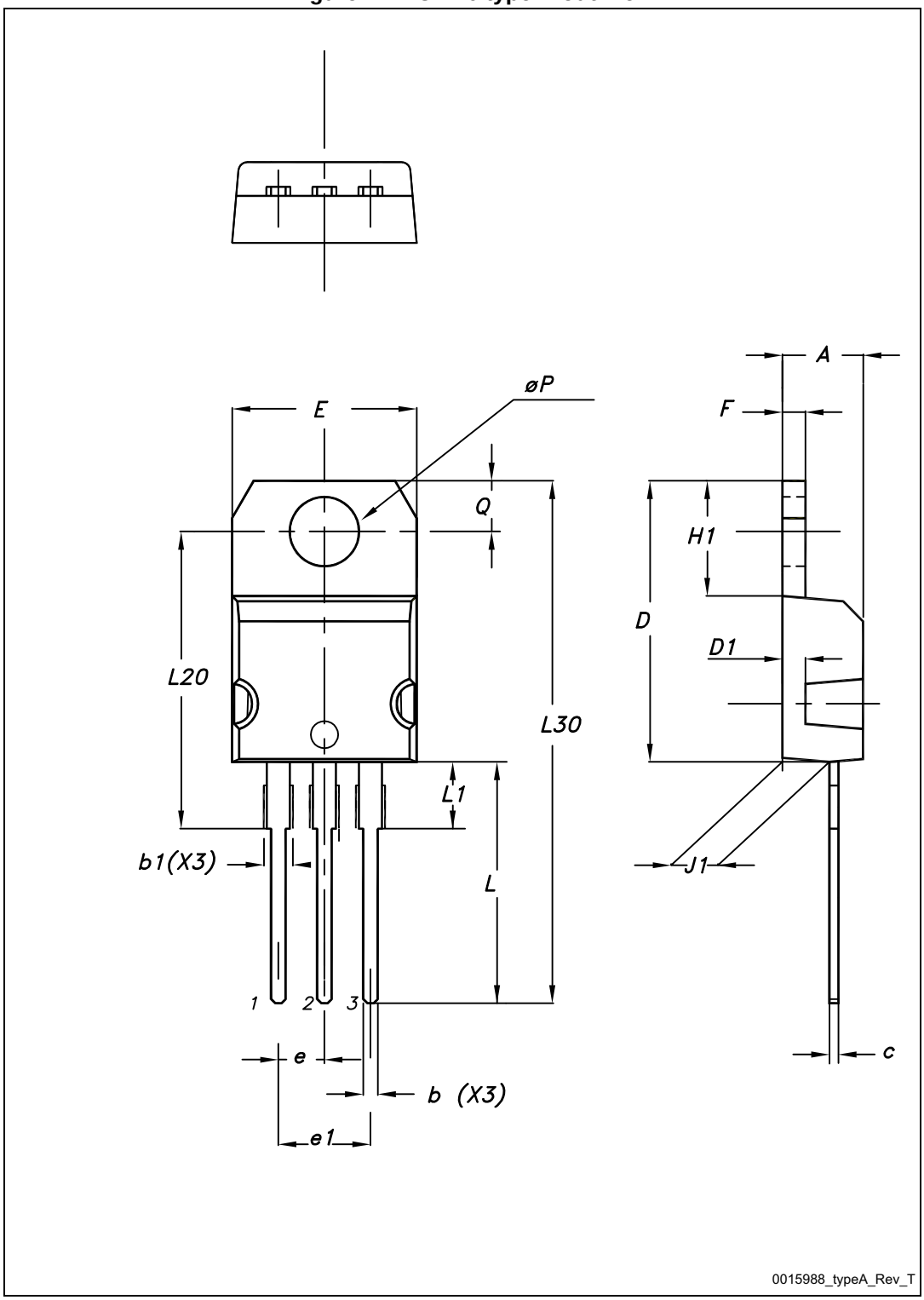


Table 8. TO-220 type A mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
b	0.61		0.88
b1	1.14		1.70
c	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10		10.40
e	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13		14
L1	3.50		3.93
L20		16.40	
L30		28.90	
øP	3.75		3.85
Q	2.65		2.95

5 Packing information

Table 9. D²PAK (TO-263) tape and reel mechanical data

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	10.5	10.7	A		330
B0	15.7	15.9	B	1.5	
D	1.5	1.6	C	12.8	13.2
D1	1.59	1.61	D	20.2	
E	1.65	1.85	G	24.4	26.4
F	11.4	11.6	N	100	
K0	4.8	5.0	T		30.4
P0	3.9	4.1			
P1	11.9	12.1	Base qty		1000
P2	1.9	2.1	Bulk qty		1000
R	50				
T	0.25	0.35			
W	23.7	24.3			

Figure 23. Tape

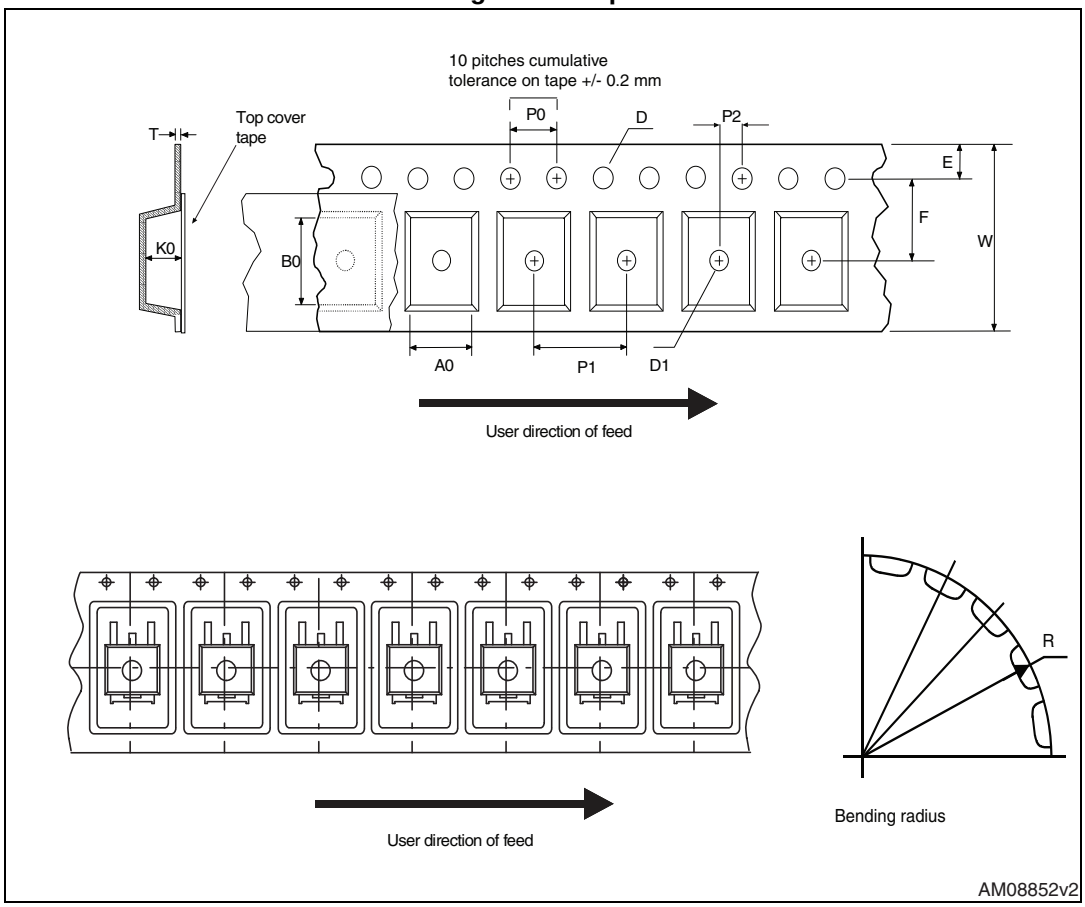
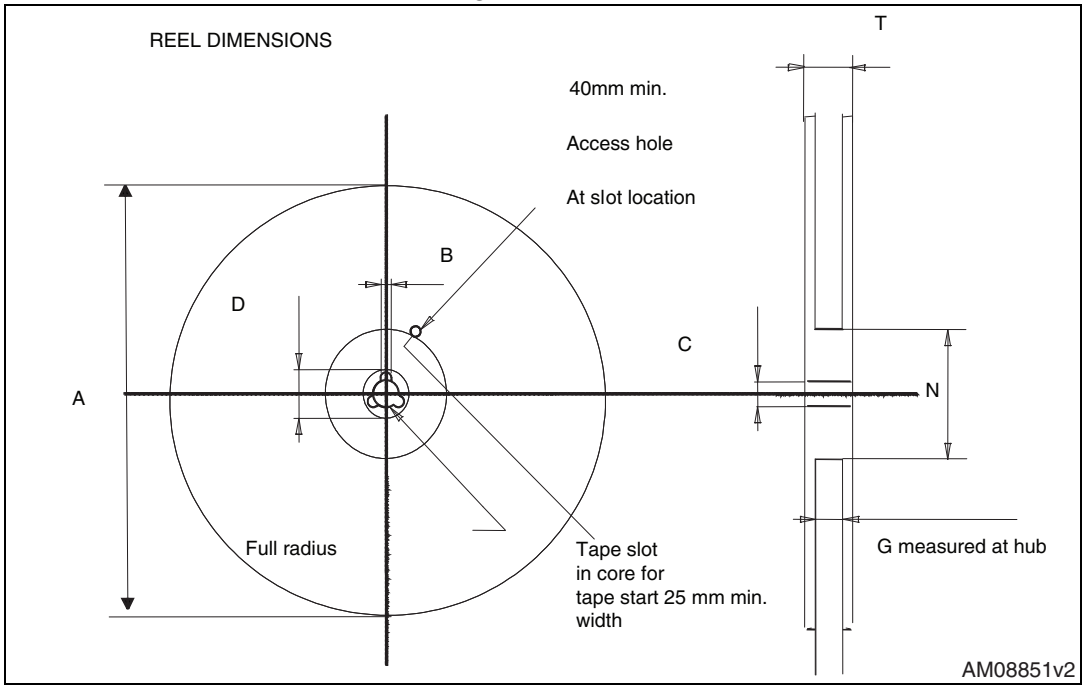


Figure 24. Reel



6 Revision history

Table 10. Document revision history

Date	Revision	Changes
05-Aug-2010	1	Initial release.
02-Sep-2010	2	Updated title on cover page and *Table 4: On/off states*.
07-Apr-2011	3	Document status promoted from preliminary data to datasheet.
10-Oct-2011	4	Inserted new device in D^2PAK: Updated: *Table 2: Absolute maximum ratings*, *Table 3: Thermal data* and *Section 4: Package information* with the new device. Inserted *Section 5: Packing information*. Minor text changes.
12-Dec-2011	5	– *Figure 9: Output capacitance stored energy* has been updated. – *Figure 10: Normalized gate threshold voltage vs temperature* has been updated. – *Figure 11: Normalized on-resistance vs temperature* has been updated. – *Figure 12: Normalized B_{VDSS} vs temperature* has been updated.
21-Dec-2011	6	Updated: *Table 2: Absolute maximum ratings* (V_{ISO} value for TO-220FP)
10-May-2012	7	*Figure 6: Gate charge vs gate-source voltage* has been updated.
01-Jul-2013	8	– The part number STF34NM60N has been moved to a separate datasheet. – Added: MOSFET ruggedness parameter and *3* on *Table 2* – Modified: I_D value on *Table 5* and typical values for $t_{d(on)}$, t_r, $t_{d(off)}$ and t_f, max values for I_{SD} and I_{SDM}, I_{SD} for V_{SD}, typical value and I_{SD} for t_{rr} – Modified: *Figure 6*, *7*, *12* and *13* – Minor text changes
20-Mar-2015	9	– The part number STW34NM60N has been moved to a separate datasheet. – Updated *Section 4: Package information*. – Minor text changes.